

<b>Notice of References Cited</b>		Application/Control No. 10/801,697	Applicant(s)/Patent Under Reexamination ISHII ET AL.	
		Examiner David E. Graybill	Art Unit 2822	Page 1 of 4

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<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination ISHII ET AL.	
	Examiner David E. Graybill	Art Unit 2822	Page 2 of 4

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<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination ISHII ET AL.	
		Examiner David E. Graybill	Art Unit 2822	Page 3 of 4

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		Examiner David E. Graybill	Art Unit 2822	Page 4 of 4

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